



FPD Materials and Components Japan TC Chapter and FPD Metrology Japan TC Chapter Joint Meeting Meeting Summary and Minutes

SEMI Japan Standards Fall 2016 Meetings

November 9, 2016, 15:00-17:00

SEMI Japan, Tokyo, Japan

TC Chapter Announcements

FPD Materials & Components Japan TC Chapter:

SEMI Japan Standards Spring 2017 Meetings

Friday, April 7, 2017, 15:00-17:00

SEMI Japan, Tokyo, Japan

FPD Metrology Japan TC Chapter:

SEMI Japan Standards Spring 2017 Meetings

Friday, April 7, 2017, 15:00-17:00

SEMI Japan, Tokyo, Japan

Table 1 Meeting Attendees

Co-Chairs of FPD M&C Committee: Tadahiro Furukawa (Yamagata University), Yoshi Shibahara (Fujifilm)

Co-Chairs of FPD Metrology Committee: Ryoichi Watanabe (Japan Display), Akira Kawaguchi (Otsuka Electronics)

SEMI Staff: Naoko Tejima (SEMI Japan)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Sumitomo Bakelite	Eguchi	Toshimasa	Moritani	Kobayashi	Satoshi
Yamagata University	Furukawa	Tadahiro	Konica Minolta	Ochi	Keizo
HOYA	Ihara	Hirofumi	Nitto Denko	Tatsumi	Motoshige
Fujifilm	Ishizuka	Hiroshi	Sony	Tomioka	Satoshi
Teijin	Ito	Haruhiko	Japan Display	Watanabe	Ryoichi
Otsuka Electronics	Kawaguchi	Akira	SEMI Japan	Tejima	Naoko

** alphabetical order by last name*

Table 2 Leadership Changes

FPD M&C Japan TC Chapter

None.

FPD Metrology Japan TC Chapter

None.

Table 3 Ballot Results

FPD M&C Japan TC Chapter

None.

FPD Metrology Japan TC Chapter

None.

Table 4 Authorized Activities
FPD M&C Japan TC Chapter

Doc.#	Type	SC/TF/WG	Details
6102	SNARF	FPD Color Filter TF	Line Item Revision to SEMI D22-1109, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies <i>*TC Member Review is not required.</i>
6103	SNARF	FPD Color Filter TF	Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter <i>*TC Member Review is not required.</i>

FPD Metrology Japan TC Chapter

Doc.#	Type	SC/TF/WG	Details
6101	SNARF	D31 Revision TF	Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection <i>*TC Member Review is not required.</i>

NOTE 1: SNARFs and TFOFs are available for review on the SEMI Web site at:
<http://downloads.semi.org/web/wstsdbsal.nsf/TFOFSNARF>

Table 5 Authorized Ballots
FPD M&C Japan TC Chapter

Doc.#	When	SC/TF/WG	Details
6103	Cycle 9, 2016	FPD Color Filter TF	Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter

FPD Metrology Japan TC Chapter

Doc.#	When	SC/TF/WG	Details
6101	Cycle 9, 2016	D31 Revision TF	Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection

Table 6 New Action Items
FPD M&C Japan TC Chapter

Item #	Assigned to	Details
FPD M&C 161109-01	SEMI Staff	To submit Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter for Cycle 9, 2016.
FPD M&C 161109-02	SEMI Staff	To check if the SNARF should be resubmitted, when Scope will be widen and Title will be changed (Doc.#6014).

FPD Metrology Japan TC Chapter

Item #	Assigned to	Details
FPD Met 161109-01	SEMI Staff	To submit Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection. for Cycle 9, 2016.

Table 7 Previous Meeting Action Items
FPD M&C Japan TC Chapter

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD M&C 160701-01	SEMI Staff	To forward adjudication result of Doc.#6010 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-02	SEMI Staff	To forward adjudication result of Doc.#6011 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-03	SEMI Staff	To forward adjudication result of Doc.#6012 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-04	SEMI Staff	To forward adjudication result of Doc.#6013 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-05	SEMI Staff	To contact Mr. Otsuka and ask him his intention, and request him to send his replacement, if he will decline the co-leader position. ... Open

FPD Metrology Japan TC Chapter

None.

[Common Part 1]

1 Welcome, Reminders, and Introductions

Tadahiro Furukawa, committee co-chair, called the meeting to order at 15:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 SEMI Staff Report

Naoko Tejima gave the SEMI staff report. This report included SEMI Global 2016 Calendar of Events, 2016 SEMI Standards Excellence Award, Global Standards Meeting Schedule, SEMICON Europa, North America Standards Fall 2016, SEMICON Japan Standards Meetings 2016, 2016 Critical Dates for SEMI Standards Ballots, A&R Ballot Review, SEMI Standards Publication, PPT Template Updates, and Contact Information.

Attachment: 01_SEMI_Staff_Report_161109

3 Liaison Reports

3.1 FPD Metrology Korea TC Chapter

Naoko Tejima reported for the FPD Metrology Korea TC Chapter. This report included Leadership, Current Committee Organization, Meeting Information, Major Updates, Subcommittee/TF/WG Updates and Contact Information

- *GCS approval request was sent from Korea, however, there is only document number(it was wrong number) and title. Some contents of the documents should be attached.*
- *The method of GCS should be improved.*

Attachment: 02_Korea_FPD_Liaison_Report_November_2016_161109

3.2 FPD Metrology Taiwan TC Chapter

Naoko Tejima reported for the FPD Metrology Taiwan TC Chapter. This report included Leadership, Current Committee Organization, Meeting Information, Taiwan FPD TC Chapter Highlights and Contact Information.

Attachment: 03_Taiwan_FPD_Liaison_Report_November_2016_161109

[FPD Materials and Components Japan TC Chapter Part]

4 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

It was pointed out as follows:

- “To contact Mr. Otsuka and ask him ... the co-chair position.” should be corrected to “To contact Mr. Otsuka and ask him ... the co-leader position.” in “Table 6 New Action Items”

Motion: To approve the minutes of the previous meeting as written after the above point is corrected.

By / 2nd: Ryoichi Watanabe (Japan Display) / Akira Kawaguchi (Otsuka Electronics)

Discussion: None

Vote: 9 in favor and 0 opposed. **Motion passed.**

Attachment: 04_JA_FPD_M+C_Previous_Mtg_Minutes_161109

5 Subcommittee and Task Force Reports

5.1 Polarizing Film Task Force

Hiroshi Ishizuka reported for the Polarizing Film Task Force.

- Working for the 1st draft of *Doc. 6006, New Standard: Test method for measurements of dimension of films for FPD – contour matching method.*
- Discussing *Doc. 6014 Revision to SEMI D60-0710: Test Method of Surface Scratch Resistance for FPD Polarizing Film and Its Materials.* Scope will be widened and Title will be changed.

Action Item: SEMI to check if the SNARF should be resubmitted in the above case.

5.2 Flexible Display Task Force

Tadahiro Furukawa reported for the Flexible Display Task Force.

- Drafting *Doc. 5977, New Standard, Test Method of Water Vapor Barrier Property for Plastic Films with High Barrier for Electronic Devices.*

5.3 FPD Color Filter Task Force

Tadahiro Furukawa reported for the *FPD Color Filter Task Force*. The following 2 documents are for 5-year review.

- SEMI D22-1109, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies.
>> needs to revise “Related Documents”

Motion: To approve SNARF, *Line Item Revision to SEMI D22-1109, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies*

By / 2nd: Ryoichi Watanabe (Japan Display) / Hirofumi Ihara (HOYA)

Discussion: None.

Vote: 9 in favor and 0 opposed. **Motion passed.**

Attachment: 05_SNARF_of_Line_Item_Revision_to_D22_161109

- SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter
>> Sub-type “Measurement Method” is not suitable to the current regulation.

Motion: To approve SNARF, *Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter*

By / 2nd: Ryoichi Watanabe (Japan Display) / Hirofumi Ihara (HOYA)

Discussion: None.

Vote: 9 in favor and 0 opposed. **Motion passed.**

Attachment: 06_SNARF_of_Line_Item_Revision_to_D63_161109

Action Item: SEMI to submit Line Item Revision ballot of D63 for Cycle 9, 2016

- SEMI D55-0310, Guide for Evaluation Method of Color Performance for Color Filter Assemblies (Evaluation Method of Color Purity)
>> needs to change “Referenced Standards and Documents”
>> continuously to discuss

5.4 FPD Mask Task Force

Hirofumi Ihara reported for the *FPD Mask Task Force* that there were nothing to report..

6 Old Business

6.1 Previous Meeting Action Items

Naoko Tejima reviewed the previous meeting action items.

Table 8 Previous Meeting Action Items
FPD M&C Japan TC Chapter

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD M&C 160701-01	SEMI Staff	To forward adjudication result of Doc.#6010 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-02	SEMI Staff	To forward adjudication result of Doc.#6011 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-03	SEMI Staff	To forward adjudication result of Doc.#6012 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-04	SEMI Staff	To forward adjudication result of Doc.#6013 to the ISC A&R Subcommittee for procedural review. ... Closed
FPD M&C 160701-05	SEMI Staff	To contact Mr. Otsuka and ask him his intention, and request him to send his replacement, if he will decline the co-leader position. ... Open

7 New Business

None.

[FPD Metrology Japan TC Chapter Part]

8 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: To approve the minutes of the previous meeting as written.

By / 2nd: Akira Kawaguchi (Otsuka Electronics) / Keizo Ochi (Konica Minolta)

Discussion: None

Vote: 9 in favor and 0 opposed. **Motion passed.**

Attachment: 07_JA_FPD_Met_Previous_Mtg_Minutes_161109

9 Subcommittee and Task Force Reports

9.1 D31 Revision Task Force

Keizo Ochi reported for the D31 Revision Task Force.

- SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection
>> Sub-type “Definition of Measurement” is not suitable to the current regulation.

Motion: To approve SNARF, *Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection.*

By / 2nd: Keizo Ochi (Konica Minolta) / Akira Kawaguchi (Otsuka Electronics)

Discussion: None.

Vote: 9 in favor and 0 opposed. **Motion passed.**



Motion: To submit ballot of *Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection* for Cycle 9, 2016.

By / 2nd: Keizo Ochi (Konica Minolta) / Akira Kawaguchi (Otsuka Electronics)

Discussion: None.

Vote: 9 in favor and 0 opposed. **Motion passed.**

Attachment: 08_SNARF_of_Line_Item_Revision_to_D31_161109

Action Item: SEMI to submit Line Item Revision ballot of D31 for Cycle 9, 2016

10 Old Business

None.

11 New Business

None.

[Common Part 2]

12 Action Item Review

12.1 New Action Items

Naoko Tejima reviewed the new action items. These can be found in the New Action Items table at the beginning of these minutes.

13 Next Meeting and Adjournment

The next meeting of the FPD Materials and Components Japan TC Chapter is scheduled for Friday, April 7, 2017, 15:00-17:00, SEMI Japan, Tokyo, Japan.

The next meeting of the FPD Metrology Japan TC Chapter is scheduled for Friday, April 7, 2017, 15:00-17:00, SEMI Japan, Tokyo, Japan.

See <http://www.semi.org/en/events> for the current list of meeting schedules.

Having no further business, a motion was made to adjourn. Adjournment was at 17:00.



Respectfully submitted by:
Naoko Tejima
Manager, Standards
SEMI Japan
Phone: +81.3.3222.5804
Email: ntejima@semi.org

Minutes approved by:

Tadahiro Furukawa (Yamagata University), Co-chair of FPD Materials & Components Japan TC Chapter	April 7, 2017
Yoshi Shibahara (Fujifilm) , Co-chair of FPD Materials & Components Japan TC Chapter	April 7, 2017
Ryoichi Watanabe (Japan Display), Co-chair of FPD Metrology Japan TC Chapter	April 7, 2017
Akira Kawaguchi (Otsuka Electronics) , Co-chair of FPD Metrology Japan TC Chapter	April 7, 2017

Table 9 Index of Available Attachments #1

#	<i>Title</i>
1	SEMI_Staff_Report_161109
2	Korea_FPD_Liaison_Report_November_2016_161109
3	Taiwan_FPD_Liaison_Report_November_2016_161109
4	JA_FPD_M+C_Previous_Mtg_Minutes_161109
5	SNARF_of_Line_Item_Revision_to_D22_161109
6	SNARF_of_Line_Item_Revision_to_D63_161109
7	JA_FPD_Met_Previous_Mtg_Minutes_161109
8	SNARF_of_Line_Item_Revision_to_D31_161109

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.